R&D of the Test Device of CMS-GEM Electronics Board Zihan Liang, Zhihua Xue

Introduction

-CMS-GEM Electronics Board(GEB) is a component of CMS-GEM detector. PKU HEP group designed and produced GE2/1 GEB for CMS

-Designed a new test device by Xilinx FPGA to automatically test the connectivity.

-The new test device has the function of Bit Error Test in 200MHz differential signal.



VFAT3 chips work as amplifiers to collect electric signal from readout board. Electronics Board transfers data between VFAT3 chips and OptHybrid board, and provides power supply.

One OptHybrid board collects data from many VFAT3 chips and sends to CMS-DAQ.



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Test Device

Each Electronics Board has more than 270 high speed differential signal circuits. We have to test all circuits on every boards.

A new test device based on Spartan-6 FPGA is designed. PCB design, FPGA program and PC program are all independently developed.



Bit Error Rate Test & Eye Graph

The new test device have an additional function of Bit Error Rate test in 200MHz differential signal by PRBS.

Use the same PCB design and change some matching resistance.

This device can take Bit Error Rate test in 200MHz differential signal. Also send result to PC.





Eye graph of GEB prototype tested by this device and oscilloscope

Result

graph with oscilloscope. the GEB test.





Look at LED bulbs by eye, to check the circuit.

Record the result on paper.

Auto-Check the circuit by FPGA, and send the result to PC.

Use LabView to display and record the result on digital format.

The new Test Device can improve the speed and accuracy of circuit connectivity test, and record the test result in digital format.

Take Bit Error Rate test on GEB prototype and get the result of BER<10⁻¹², and take the eye

The mass production of GE2/1 Electronics Board is ongoing. The new test device will be used in

More Information

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